

SPC and Order Statistics: Burr Type XII Model

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Abstract — This paper presents a simple SRGM, the Burr Type XII Non Homogeneous Poisson Process (NHPP) model is used as a control mechanism based on order statistics of the cumulative quantity between observations of time domain failure data. This model has the ability of modeling both reliability improving and deteriorating systems and has gained wide acceptance. The Maximum Likelihood Estimation (MLE) method is used to derive the point estimators. We have applied the model to sets of existing software failure datasets to assess the failure process using SPC.

Keywords — Burr type XII model, NHPP, MLE, Statistical Process Control, Order Statistics.

I. INTRODUCTION

Modern society relies heavily on the correct operation of software and from user's point of view, the software plays an important role in systems of both safety-critical and civil applications. Software Reliability plays an important role in software quality. As more and more software is creeping into the embedded system, reliability has become an essential characteristic for the software. There are many software reliability models that are based on the times of occurrences of errors in debugging of the software. It is also possible to do asymptotic likelihood inference for software reliability models based on order statistics or Non – Homogeneous Poisson Processes (NHPP) with asymptotic confidence levels for interval estimates of parameters. In particular, interval estimates from these models are obtained for the conditional failure rate of the software, given the data from the debugging process. The data can be either grouped or ungrouped.

Software Reliability can prevent major faults that have the possibility of taking human life, money and time. For this a number of models have been developed for better predictions. A common

approach for measuring software reliability is by using an analytical model whose parameters are generally estimated from available software failure data. Reliability quantities have been defined with respect to time, although it is possible to define them

with respect to other variables. In reliability study there are two characteristics of a random process: 1) the probability distribution of the random variables, i.e., Poisson and 2) the variation of the process with time. A random process whose probability distribution varies with time is called non homogeneous. The random process for time variation we can define two functions, the mean value function $m(t)$, as the average cumulative failures associated with each time point and the failure intensity function as the rate of change of mean value function.

Order statistics are used in a wide variety of practical situations. Their use in characterization problems, detection of outliers, linear estimation, study of system reliability, life-testing, survival analysis, data compression and many other fields can be seen from the many books example [1][2].

This paper presents a control mechanism is proposed which is based on the order statistics of cumulative quantity between observations of time domain failure data using mean value function of Burr Type XII distribution which is based on NHPP. The Burr Type XII distribution model with order statistics approach is applied on live data sets and the results are exhibited at the end of this paper.

II. ORDER STATISTICS

Order statistics deals with properties and applications of ordered random variables and functions of these variables. The use of order statistics is significant when inter failure time is less or failures are frequent. Let A denote a continuous random variable with probability density function, $f(a)$ and cumulative distribution function, $F(a)$, and let (A_1, A_2, \dots, A_k) denote a random sample of size k drawn on A . The original sample observations may be unordered with respect to magnitude. A transformation is required to produce a corresponding ordered sample. Let $(A(1), A(2), \dots, A(k))$ denote the ordered random sample such that $A(1) < A(2) < \dots < A(k)$; then $(A(1), A(2), \dots, A(k))$ are collectively known as the order statistics derived from the parent A . The various distributional characteristics can be known from Balakrishnan and Cohen [1].

We compute the software failures process through Failure control chart based on the cumulative inter failure data. The transformation being applied is, the failure data is made into groups of 4, 5 and then cumulated. The inter failure time data represent the time laps between every two consecutive failures. On the other hand if a reasonable waiting time for failures is not a serious problem we can group the inter failure time data into non overlapping successive subgroups of size 4 or 5 and add the failures times with needs of groups. For instance if a data of 100 inter failure times are available, we can group them into 20 disjoint subgroups of size 5. The sum totals in each subgroup would represent the time laps between every 5th failures. In the theory of statistics such a subtotal is defined as the 5th order statistics in a sample of size 5. In general for inter failure data of size 'm' if 'r' is any natural number less than m and preferably a factor of 'm' we can expediently divide the data into 'p' disjoint subgroups (p=m/r) and the cumulative total meets subgroup indicate the time between every rth failure.

The probability distribution of such a time laps would be better in the r th order statistic in a subgroup of size 'r'. This would be equal to the rth power of the distribution function of the original variable. The parameters of the mean value function with the revised distribution function would determine the control limits of a new control chart involving order statistics. Hence they need a separate study.

In the present paper we have taken r = 4, 5 and the Burr Type XII model. Choice of r beyond 5 may create an overly long waiting time for the occurrence of every rth failure. 'a', 'b' and 'c' are Maximum Likelyhood Estimates (MLEs) of parameters and the values can be calculated using iterative method for the given cumulative time between failures data. Using 'a' and 'b' and 'c' values we can compute m(t).

III. ILLUSTRATING THE MLE METHOD

Burr Type XII Model

This paper proposes estimation of software reliability using order statistics approach based on Burr Type XII distribution model. The Burr distribution has a flexible shape and controllable scale and location which makes it appealing to fit to data. It is frequently used to model insurance claim sizes. The mean value function and intensity function of Burr Type XII NHPP model are as follows [8][15].

The Cumulative distributive function (CDF) is given

$$m(t) = \int_0^t \lambda(t) dt = a \left[1 - (1+t^c)^{-b} \right] = a F(t)$$

The Probability Density Function (PDF) of Burr XII distribution are given, respectively by

$$\lambda(t) = a \left(\frac{cbt^{c-1}}{(1+t^c)^{b+1}} \right) = a f(t)$$

Mathematical Derivation for Parameter Estimation

We develop expressions to estimate the parameters of the Burr type XII model based on time domain data using order statistics approach. Parameter estimation is very significant in software reliability prediction. Once the analytical solution form is known for a given model, parameter estimation is achieved by applying a well-known estimation, Maximum Likelihood Estimation (MLE).

The main idea behind Maximum Likelihood parameter assessment is to decide the parameters that maximize the probability (likelihood) of the specimen data. In other words, MLE methods are versatile and applicable to most models and for different types of data.

The mean value function of Burr type XII model is given by [8]

$$m(t) = a \left[1 - (1+t^c)^{-b} \right], \quad t \geq 0 \quad (1)$$

The parameters a, b, c are estimated with Maximum Likelihood (ML) estimation. In order to group the Time domain data into non overlapping successive sub groups of size r, we need to take m(t) to the power r.

$$m(t) = \left[a \left(1 - (1+t^c)^{-b} \right) \right]^r \quad (2)$$

To get the estimates of 'a', 'b' and 'c' for a sample of n units, the likelihood function must be obtained first [11].

$$L = e^{-m(t)} \prod_{i=1}^n m'(t_i) \tag{3}$$

$$L = e^{-a[1-(1+t^c)^{-b}]^r} \prod_{i=1}^n r \left[a - \frac{a}{(1+t^c)^b} \right]^{r-1} \frac{abct^{c-1}}{(1+t^c)^{b+1}}$$

$$\begin{aligned} \text{Log} L = & -a^r \left[1 - \frac{1}{(1+t^c)^b} \right]^r + \sum_{i=1}^n \log r + \sum_{i=1}^n (r-1) \log \left[a - \frac{a}{(1+t_i^c)^b} \right] + \\ & \sum_{i=1}^n (\log a + \log b + \log c + (c-1) \log t_i - (b+1) \log(t_i^c + 1)) \end{aligned}$$

Differentiating Log L with respect to ‘a’, and equating to 0 (i.e., $\frac{\partial \text{Log} L}{\partial a} = 0$) we get

$$a^r = n \left[\frac{(t^c + 1)^b}{(t^c + 1)^b - 1} \right]^r \tag{4}$$

Differentiating Log L with respect to ‘b’ and equating to ‘0’.

$$\begin{aligned} \frac{\partial \text{Log} L}{\partial b} = 0 \\ g(b) = \left[\left(\frac{nr}{(t+1)^b - 1} \right) \log \left(\frac{1}{1+t} \right) \right] - \sum_{i=1}^n \left[\frac{r-1}{(1+t_i)^b - 1} \log \left(\frac{1}{1+t_i} \right) \right] + \frac{n}{b} - \sum_{i=1}^n \log(t_i + 1) \end{aligned} \tag{5}$$

Again differentiating $g(b)$ with respect to ‘b’ and equating to 0 (i.e., $\frac{\partial^2 \text{Log} L}{\partial b^2} = 0$)

$$g'(b) = -nr \log \left(\frac{1}{1+t} \right) \frac{(t+1)^b \log(t+1)}{[(t+1)^b - 1]^2} + \sum_{i=1}^n \log \left(\frac{1}{1+t_i} \right) \frac{(t_i+1)^b \log(1+t_i)}{[(t_i+1)^b - 1]^2} - \frac{n}{b^2} \tag{6}$$

Differentiating Log L with respect to ‘c’ and equating to ‘0’.

$$\frac{\partial \text{Log} L}{\partial c} = 0$$

$$g(c) = -nr \frac{\log t}{(1+t^c)} + \sum_{i=1}^n (r-1) \left(\frac{\log t_i}{1+t_i^c} \right) + \frac{n}{c} + \sum_{i=1}^n \left[\log t_i - \left(\frac{2}{1+t_i^c} \right) t_i^c \cdot \log t_i \right] \tag{7}$$

Again differentiating $g(b)$ with respect to ‘b’ and equating to 0 (i.e., $\frac{\partial^2 \text{Log} L}{\partial c^2} = 0$)

$$\begin{aligned} g'(c) = nr \left[2 \log t \cdot \frac{t^c}{(1+t^c)^2} \right] \\ - \sum_{i=1}^n \left[(r-1) 2 \log t_i \cdot \frac{t_i^c}{(1+t_i^c)^2} \right] - \frac{n}{c^2} + \sum_{i=1}^n \left[\log t_i - 2 \log t_i \left(t_i^c \log t_i \cdot \frac{1}{(1+t_i^c)^2} \right) \right] \end{aligned} \tag{8}$$

The parameters ‘b’ and ‘c’ are estimated by iterative Newton- Raphson using

$$\begin{aligned} b_{n+1} &= b_n - \frac{g(b_n)}{g'(b_n)} \\ c_{n+1} &= c_n - \frac{g(c_n)}{g'(c_n)} \end{aligned}$$

Which are substituted in Eq.(4) to determine ‘a’.

Estimated Parameters and their Control Limits

[9] estimated the parameters using maximum likelihood estimation using interfailure time data. The control limits for the chart are defined in such a manner that the process is considered to be out of control when the time to observe exactly one failure is less than LCL or greater than UCL. Our aim is to monitor the failure process and detect any change of the intensity parameter.

When the process is normal, there is a chance for this to happen and it is commonly known as false alarm. The traditional false alarm probability is to set to be 0.27% although any other false alarm probability can be used [12]. The actual acceptable false alarm probability should in fact depend on the actual product or process [13].

The estimated parameters and the calculated control limits of the Failure control Chart for Musa and SYS2 data sets with the false alarm risk, $\alpha = 0.0027$ are given in Table 1. Using the estimated parameters and the estimated limits, we calculated the control limits $UCL = m(t_u)$, $CL =$

$m(t_c)$ and $LCL = m(t_l)$. They are used to find whether the software process is in control or not. The estimated values of ‘a’ and ‘b’ and ‘c’ and their control limits for both 4th -order and 5th -order statistics are as follows.

Calculation of control limits

$$T_u = 0.99865$$

$$T_c = 0.5$$

$$T_l = 0.00135$$

Table 1: Parameter estimates and Control limits of 4 & 5 order

Data Set	Order	Estimated Parameters			Control Limits		
		a	b	c	UCL	CL	LCL
Musa	4	8.50	0.927761	1.000346	8.488525	4.250000	0.011471
	5	5.40	0.939095	1.000277	5.392710	2.700000	0.007289
Sys 2	4	5.25	0.901900	1.000173	5.242913	2.624999	0.007089
	5	3.40	0.919045	1.000135	3.395410	1.6999999	0.004589

Distribution of Time between Failures

The mean value successive differences of rth order cumulative time between failures data of the considered data sets are tabulated in Table 2 to 5. Considering the mean value successive differences on y axis, failure numbers on x axis and the control limits on Failure control chart, we obtained Figure 1

to 4. A point below the control limit $m(t_l)$ indicates an alarming signal. A point above the control limit $m(t_u)$ indicates better quality. If the points are falling within the control limits it indicates the software process is in stable.

Table 2: Successive Differences of 4th order mean values of Musa

F.No	4-order C_TBF	m(t)	Successive Differences	F.No	4-order C_TBF	m(t)	Successive Differences
1	227	8.444910865	0.025473171	18	16358	8.498955984	0.000102605
2	444	8.470384036	0.011594542	19	18287	8.499058589	9.72543E-05
3	759	8.481978577	0.004752661	20	20567	8.499155843	0.000116243
4	1056	8.486731238	0.005882555	21	24127	8.499272086	0.000103446
5	1986	8.492613794	0.001785012	22	28460	8.499375533	7.09241E-05
6	2676	8.494398806	0.002095267	23	32408	8.499446457	7.19499E-05
7	4434	8.496494073	0.000420743	24	37654	8.499518407	4.65714E-05
8	5089	8.496914816	0.000159693	25	42015	8.499564978	2.68286E-06
9	5389	8.497074509	0.000424165	26	42296	8.499567661	5.00806E-05

10	6380	8.497498674	0.000334377	27	48296	8.499617742	2.56036E-05
11	7447	8.497833051	0.000120836	28	52042	8.499643345	8.68534E-06
12	7922	8.497953886	0.000436267	29	53443	8.499652031	1.74262E-05
13	10258	8.498390153	0.000122963	30	56485	8.499669457	3.03022E-05
14	11175	8.498513115	0.000152686	31	62651	8.499699759	9.63903E-06
15	12559	8.498665801	8.53239E-05	32	64893	8.499709398	3.98085E-05
16	13486	8.498751125	0.000136472	33	76057	8.499749207	3.33167E-05
17	15277	8.498887597	6.8387E-05	34	88683	8.499782523	

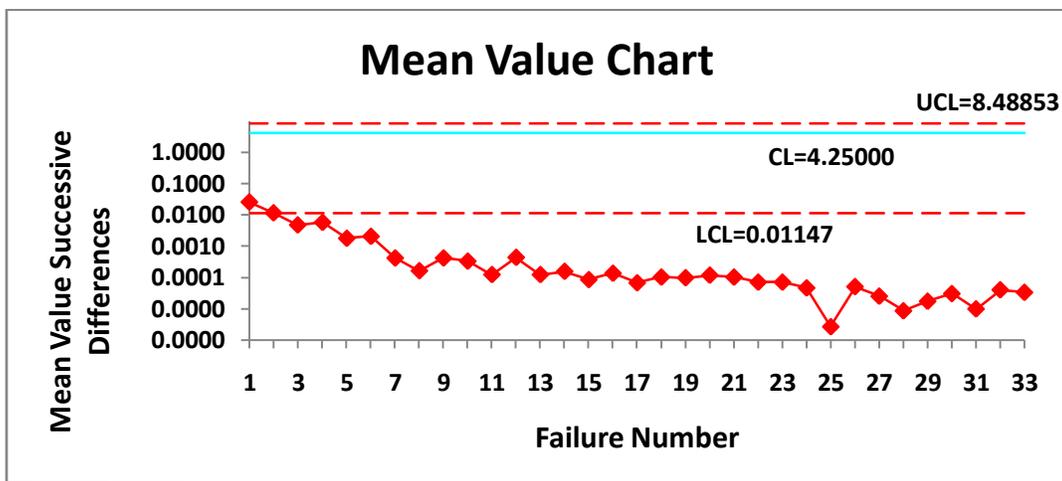


Fig 1: Failure Control Chart for Musa Dataset of order 4

Table 3: Successive Differences of 5th order mean values of Musa Dataset

F.No	5-order C_TBF	m(t)	Successive Differences	F.No	5-order C_TBF	m(t)	Successive Differences
1	342	5.377568698	0.008556681	15	17758	5.399449597	7.09183E-05
2	571	5.38612538	0.005418403	16	20567	5.399520515	9.35047E-05
3	968	5.391543783	0.004148817	17	25910	5.39961402	4.27728E-05
4	1986	5.3956926	0.001470152	18	29361	5.399656793	7.14374E-05
5	3098	5.397162753	0.001043802	19	37642	5.39972823	2.66574E-05
6	5049	5.398206554	8.71412E-05	20	42015	5.399754887	1.72349E-05
7	5324	5.398293696	0.00026667	21	45406	5.399772122	1.7414E-05
8	6380	5.398560366	0.000224782	22	49416	5.399789536	1.45114E-05
9	7644	5.398785148	0.000278761	23	53321	5.399804048	1.03283E-05
10	10089	5.399063909	7.1677E-05	24	56485	5.399814376	1.72389E-05
11	10982	5.399135586	0.000102358	25	62661	5.399831615	2.50181E-05
12	12559	5.399237944	0.000105074	26	74364	5.399856633	1.63088E-05
13	14708	5.399343018	5.64761E-05	27	84566	5.399872942	
14	16185	5.399399494	5.01026E-05				

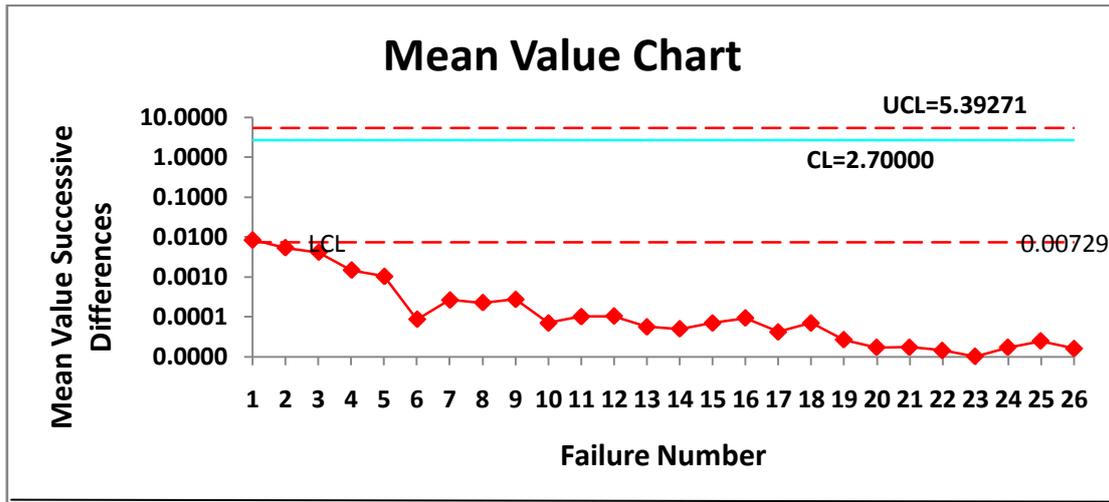


Fig 2: Failure Control Chart for Musa Dataset of order 5

Table 4: Successive Differences of 4th order mean values of Sys2 Dataset

F.No	4-order C_TBF	m(t)	Successive Differences	F.No	4-order C_TBF	m(t)	Successive Differences
1	1576	5.243152433	0.003986834	12	34467	5.249576205	5.94215E-05
2	4149	5.247139267	0.000754775	13	40751	5.249635627	5.15662E-05
3	5827	5.247894041	0.000820303	14	48262	5.249687193	2.64253E-05
4	10071	5.248714344	0.000174264	15	53223	5.249713618	1.35451E-05
5	11836	5.248888608	0.000228678	16	56160	5.249727163	2.17029E-05
6	15280	5.249117286	7.497E-05	17	61565	5.249748866	2.69314E-05
7	16860	5.249192256	0.00010168	18	69815	5.249775797	3.2021E-05
8	19572	5.249293936	0.0001148	19	82822	5.249807818	1.5982E-05
9	23827	5.249408736	8.42957E-05	20	91190	5.2498238	1.0623E-05
10	28257	5.249493032	5.23489E-05	21	97698	5.249834423	
11	31886	5.249545381	3.08239E-05				

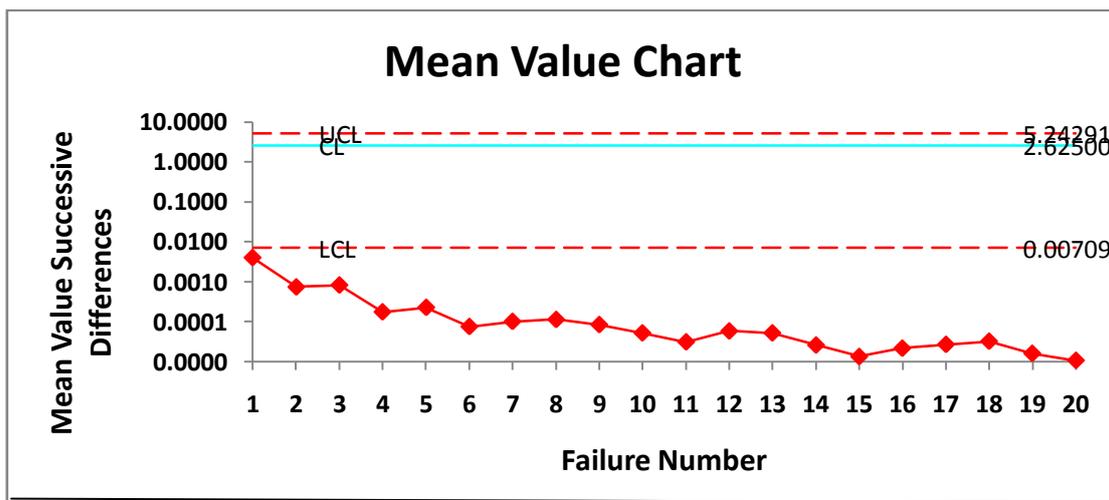


Fig 3: Failure Control Chart for Sys2 Dataset of order 4

Table 5: Successive Differences of 5th order mean values of Sys2 Dataset

F.No	5-order C_TBF	m(t)	Successive Differences	F.No	5-order C_TBF	m(t)	Successive Differences
1	2610	3.397540449	0.00094882	10	39856	3.399799166	2.53111E-05
2	4436	3.398489269	0.000648192	11	46147	3.399824477	2.15703E-05
3	8163	3.399137461	0.00024951	12	53223	3.399846047	1.39037E-05
4	11836	3.399386971	0.000139776	13	58996	3.399859951	1.60915E-05
5	15685	3.399526746	5.61415E-05	14	67374	3.399876043	1.82326E-05
6	17995	3.399582888	7.35854E-05	15	80106	3.399894275	1.18726E-05
7	22226	3.399656473	6.8023E-05	16	91190	3.399906148	6.5781E-06
8	28257	3.399724496	3.2183E-05	17	98692	3.399912726	
9	32346	3.399756679	4.24866E-05				

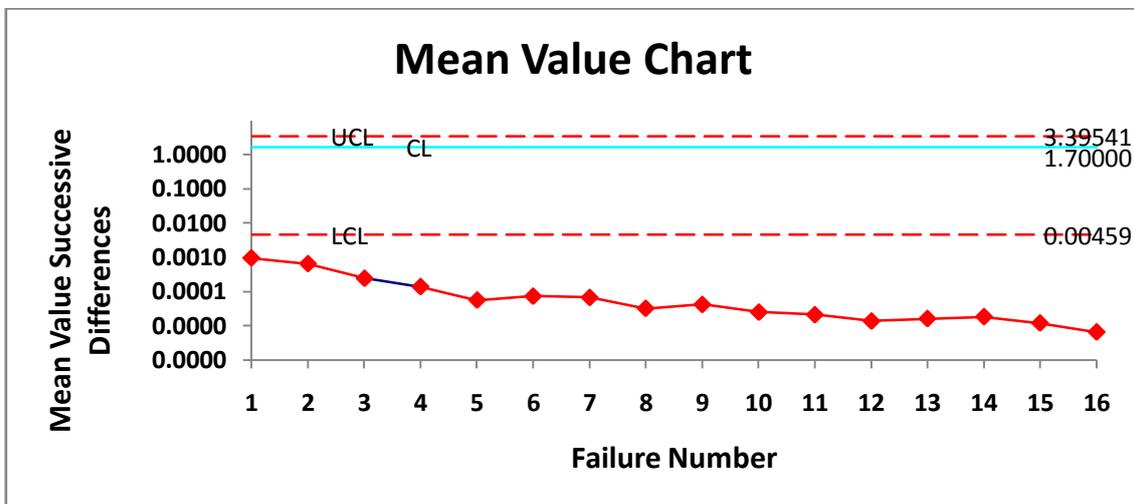


Fig 4: Failure Control Chart for Sys2 Dataset of order 5

IV. CONCLUSIONS

The 4 and 5 order failure counts are plotted through the estimated mean value function against the rth failure (i.e 4 & 5) serial order. The MLE method is used to estimate the parameters. The successive differences of the Musa dataset are fairly fluctuating within the control limits and the successive differences of Sys2 dataset have gone out of control limits. Hence we conclude that our method of estimation and the control chart are giving a Positive recommendation for their use in finding out preferable control process or desirable out of control signal.

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